

Search Notes

Application/Control No.

10/748,298

Examiner

Linh M. Nguyen

Applicant(s)/Patent under
Reexamination

HAZUCHA ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
317	172	10/20/05	mm
4	175	"	"
11	176	"	"
4	263	"	"
"	271	"	"
"	284	"	"
"	291	"	"
"	294	"	"
"	299	"	"

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR